

500V 20A N-Channel Enhancement Mode Power MOSFET

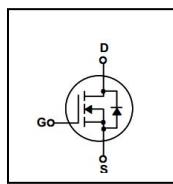
General Description

BXP20N50 is Bridgelux high voltage MOSFET family based on advanced planar DMOS technology. This advanced MOSFET family has optimized on-state resistance, and also provides superior switching performance and higher avalanche energy strength. This device family is suitable for high efficiency switch mode power supplies.

FEATURES

- $R_{DS(on)} \leq 0.3 \Omega$ @ $V_{GS} = 10V$, $I_D = 10A$
- Excellent $R_{DS(on)}$ and Low Gate Charge
- Fast switching capability
- Lead free product is acquired

SYMBOL



ASSEMBLY MESSAGE

Product Name	Package	Packaging
BXP20N50P	TO-220	Tube
BXP20N50F	TO-220F	Tube
BXP20N50A	TO-3PN	Tube

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Rating			Unit
		BXP20N50P	BXP20N50F	BXP20N50A	
Drain-Source Voltage	V_{DSS}		500		V
Drain Current	I_D		20		A
			12.5		A
Drain Current	I_{DM}		80		A
Gate-Source Voltage	V_{GSS}		± 30		V
Avalanche Energy	E_{AS}		1200		mJ
Avalanche Current (Note1)	I_{AR}		20		A
Peak Diode Recovery dv/dt (Note3)	dv/dt		5		V/ns
Power Dissipation (Note 2)	P_D	176	39	208	W
		1.41	0.31	1.66	W/ $^\circ C$
Maximum Junction Temperature	T_J		150		$^\circ C$
Storage Temperature Range	T_{STG}		-55 to 150		$^\circ C$

Note: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

2. L=6mH, $I_{AS}=20A$, $V_{DD}=50V$, $R_G=25\Omega$, Starting $T_J = 25^\circ C$

3. $I_{SD} \leq 20A$, $di/dt \leq 300A/\mu s$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ C$

THERMAL CHARACTERISTICS

Parameter	Symbol	Max.			Unit
		BXP20N50P	BXP20N50F	BXP20N50A	
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.71	3.2	0.6	°C / W
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	53	62	41	°C / W

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ C$,unless otherwise Noted)

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, ID=250\mu A$	500			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=500V, V_{GS}=0V$			1	uA
		$V_{DS}=400V, TC = 125^\circ C$			100	uA
Gate-Body Leakage Current, Forward	I_{GSS}	$V_{GS}=30V$			100	nA
Gate-Body Leakage Current, Reverse		$V_{GS}=-30V$			-100	nA
Breakdown Voltage Temperature Coefficient	$\Delta BVDSS/\Delta TJ$	$ID = 250 \mu A$		0.67		V/°C
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, ID=250\mu A$	2		4	V
Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, ID=10A$		0.24	0.3	Ω
Forward Transconductance (Note4)	g_{FS}	$V_{DS} = 50V, ID=10A$		24		S
DYNAMIC PARAMETERS						
Input Capacitance	C_{iss}	$V_{DS}=25V, V_{GS}=0V, f=1.0MHz$		2290		pF
Output Capacitance	C_{oss}			380		pF
Reverse Transfer Capacitance	C_{rss}			30		pF
SWITCHING PARAMETERS						
Turn-ON Delay Time	$t_{D(ON)}$	$VDD=250V, ID=20A, VGS = 10V, RG=25\Omega$ (Note4,5)		54		ns
Turn-ON Rise Time	t_R			166		ns
Turn-OFF Delay Time	$t_{D(OFF)}$			100		ns
Turn-OFF Fall-Time	t_F			85		ns
Total Gate Charge(Note5)	Q_G	$VDS = 400V, VGS = 10V, ID = 20A$ (Note4,5)		51		nC
Gate Source Charge	Q_{GS}			12		nC
Gate Drain Charge	Q_{GD}			20		nC
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Drain-Source Diode Forward Voltage	V_{SD}	$IS=20A, VGS=0V$			1.4	V
Diode Continuous Forward Current	I_S				20	A
Pulsed Drain-Source Current	I_{SM}				80	A
Reverse Recovery Time	t_{RR}	$VGS = 0 V, ISD = 20A$ $di/dt=100 A/\mu s$ (Note4,5)		462		ns
Reverse Recovery Charge	Q_{RR}			5		nC

Note: 4. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

5. Essentially independent of operating temperature

TYPICAL CHARACTERISTICS

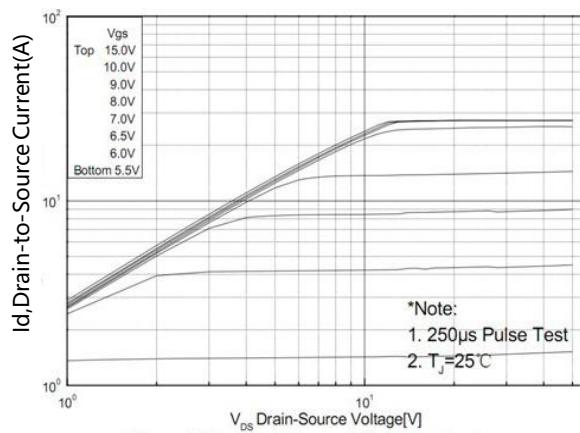


Figure1. Typical Output Characteristics

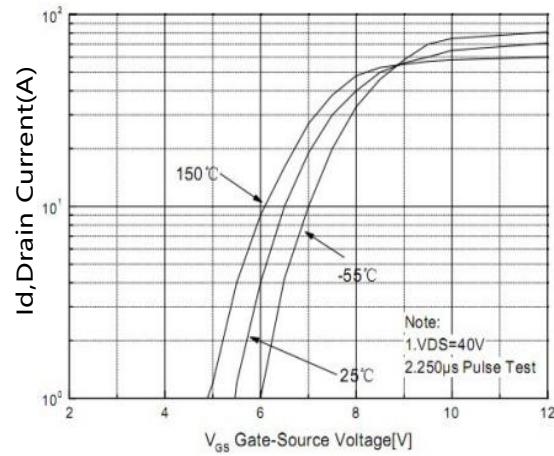


Figure2. Typical Transfer Characteristics

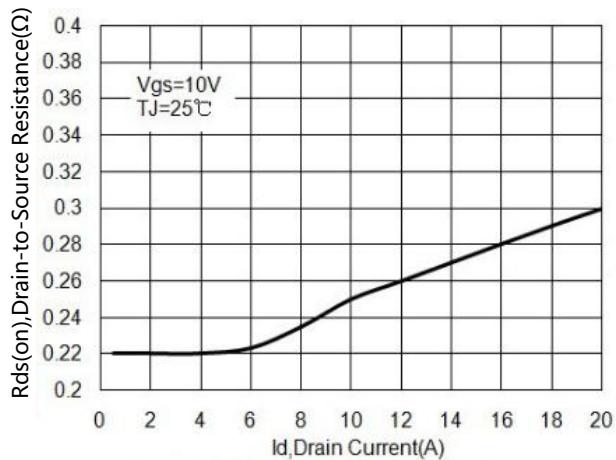


Figure3. On-Resistance versus Drain Current

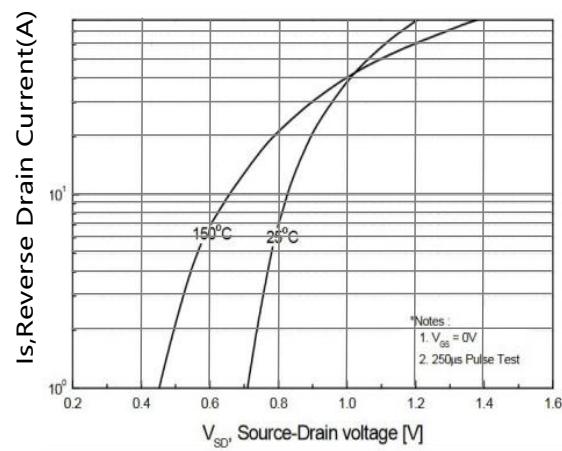
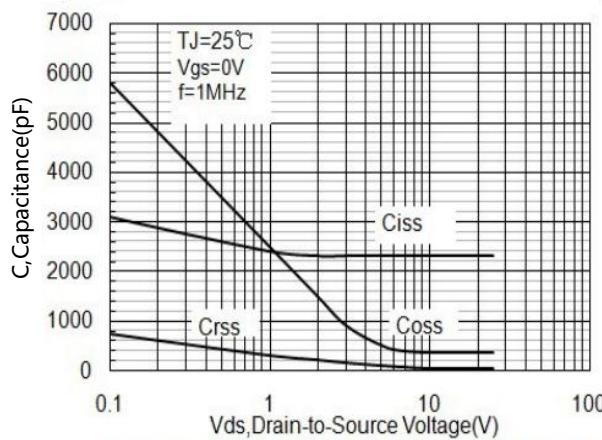
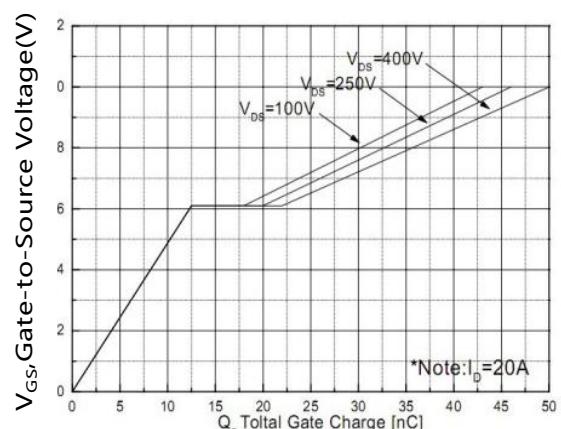


Figure4. Diode forward voltage versus Current

Figure5. Typical Capacitance versus V_{ds} Figure6. Typical Gate Charge versus V_{gs}

TYPICAL CHARACTERISTICS(Cont.)

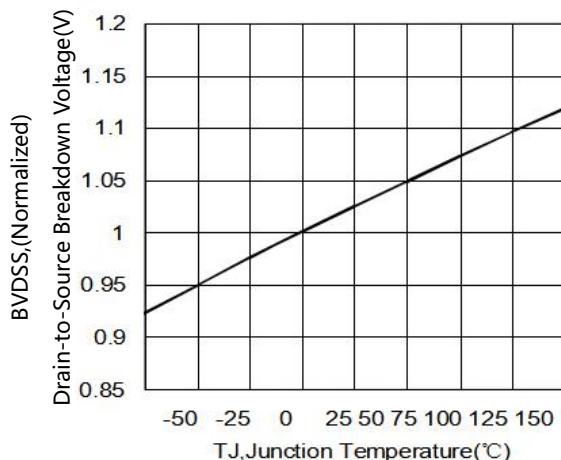
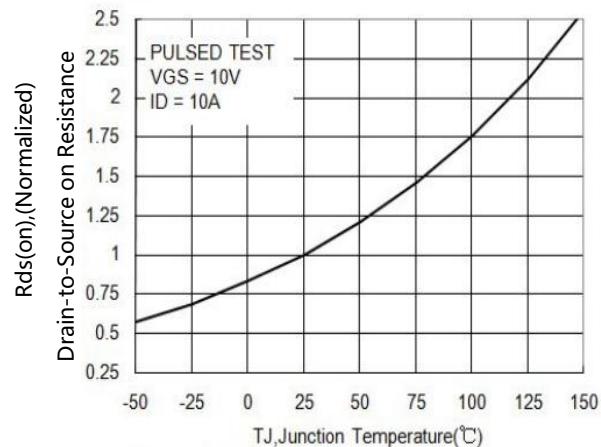
Figure7. BV_{DSs} Variation with Temperature

Figure8. On-Resistance Variation with Temperature

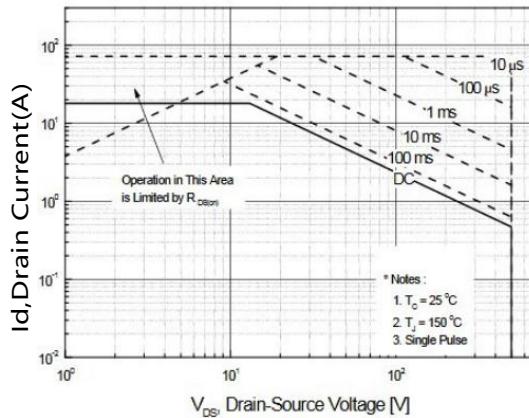


Figure9. Maximum Safe Operating Area

BXP20N50P/A

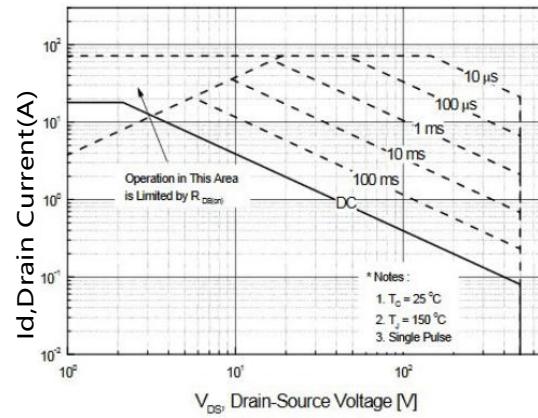
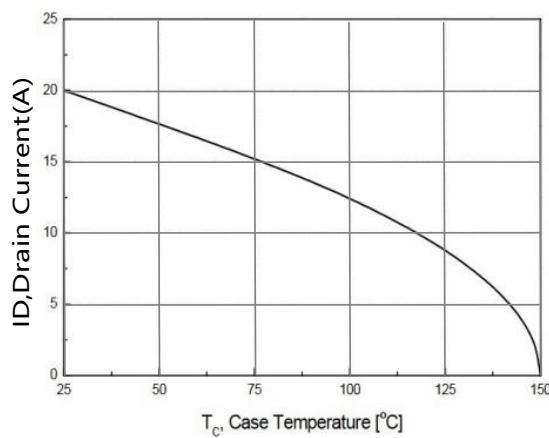
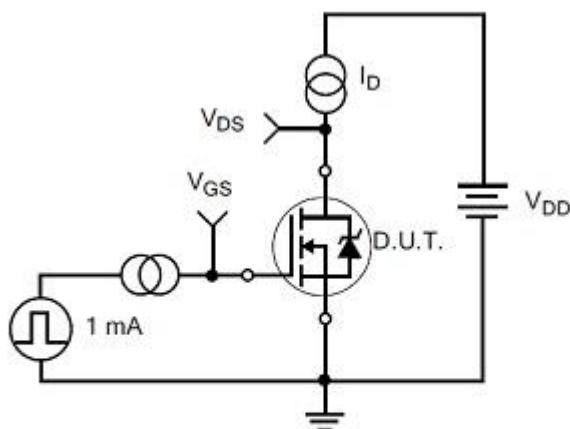


Figure9. Maximum Safe Operating Area

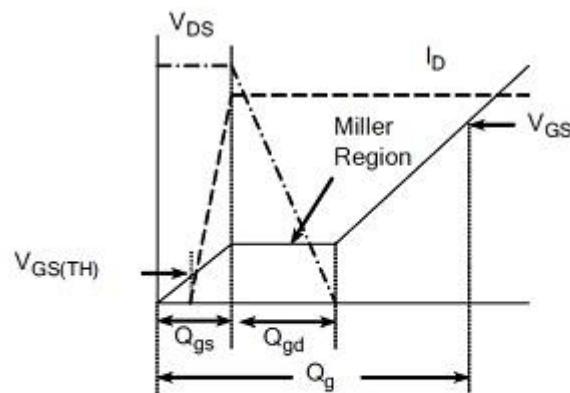
BXP20N50F

Figure10. Maximum Continuous Drain Current
versus Case Temperature

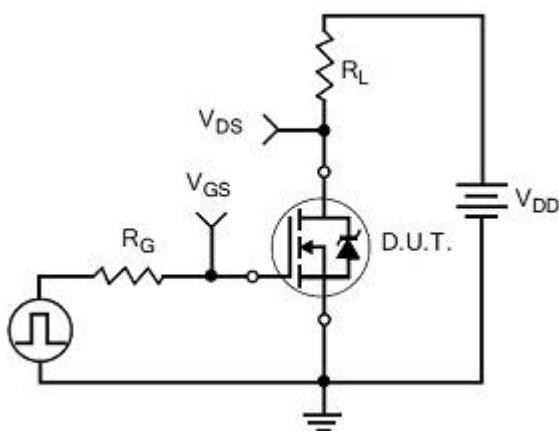
TEST CIRCUITS AND WAVEFORMS



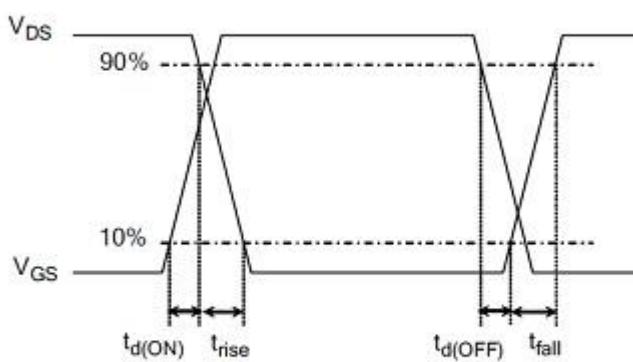
Gate Charge Test Circuit



Gate Charge Waveform

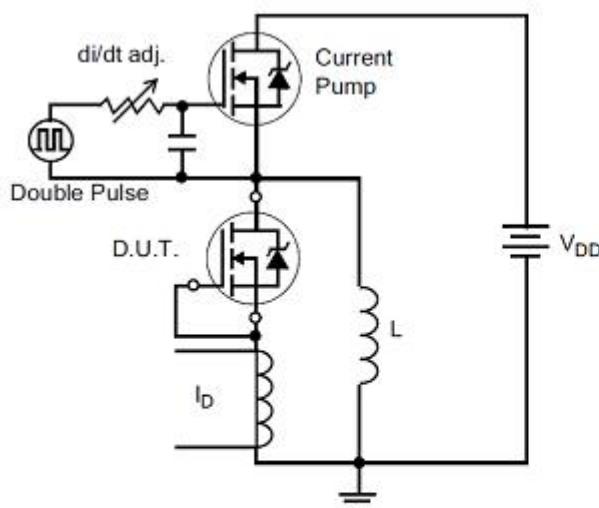


Resistive Switching Test Circuit

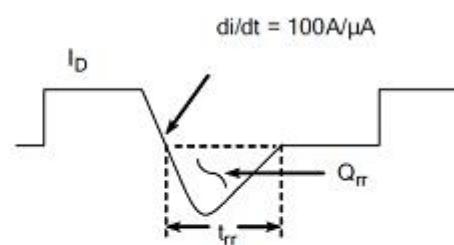


Resistive Switching Waveforms

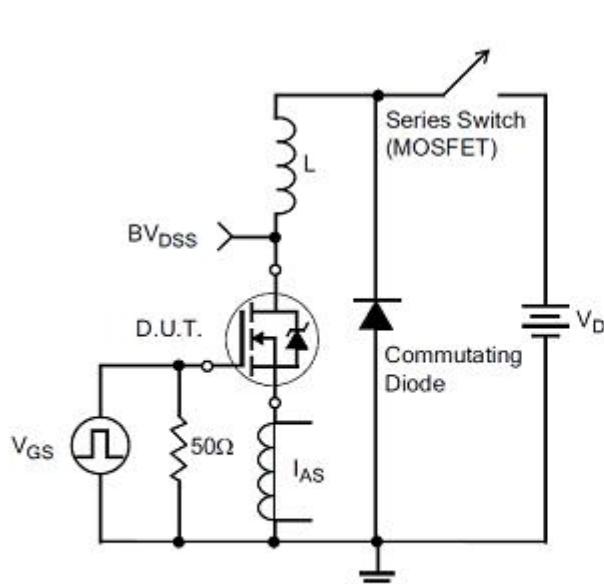
TEST CIRCUITS AND WAVEFORMS(Cont.)



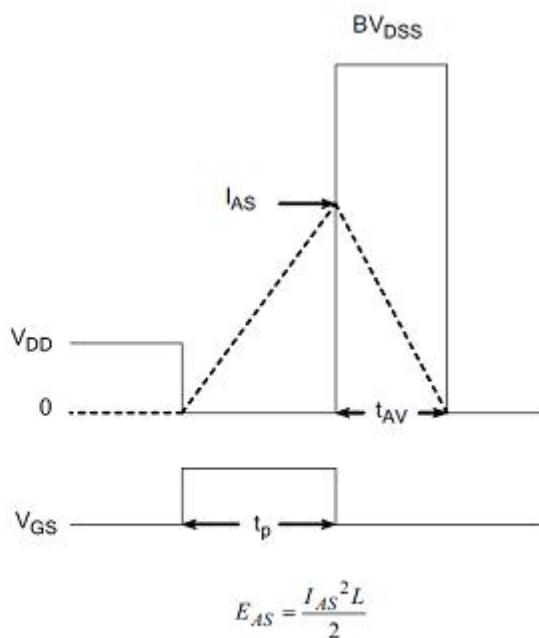
Diode Reverse Recovery Test Circuit



Diode Reverse Recovery Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

Revision history

Document revision history

Date	Revision	Changes
20-Sep-2021	1.0	First release
5-Jan-2022	1.1	Update parameter

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